



Traceability NA TC Chapter Meeting Summary and Minutes

NA Fall Meetings

Wednesday, November 15, 2023

4:00-6:00 PM Pacific Time

Online via Web Conference

TC Chapter Announcements

Next TC Chapter Meeting

TBD

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: Dave Huntley (PDF Solutions), Yaw Obeng (NIST)

SEMI Staff: Michelle Sun

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Enkris Semiconductor	<i>Tao</i>	<i>Guoqiao</i>	PDF Solutions	<i>Huntley</i>	<i>Dave</i>
Hitachi High-Tech Corporation	<i>Toyoshima</i>	<i>Yuko</i>	PEER Group Inc.	<i>Fuchigami</i>	<i>Albert</i>
Lam Research Corporation	<i>Arrendondo</i>	<i>Manuel</i>	SEMI	Sun	Michelle
National Institute of Advanced Industrial Science and Technology	<i>Kobara</i>	<i>Kazukuni</i>	Tokyo Electron Limited	<i>Akimoto</i>	<i>Toshikazu</i>
NIST - National Institute of Standards & Technology	<i>Pease</i>	<i>Michael</i>			

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
None		

Table 3 TC Chapter Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
None	

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
7136	Reapproval of SEMI T3-1213 (Reapproved 0419), Specification for Wafer Box Labels	Passed

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.



Table 5 Ratification Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>ISC A&R Action</i>	<i>A&R Forms</i>
None			

Note 1: **Passed** Ratification ballots will be submitted to SEMI publication for final processing.

Note 2: **Failed** Ratification ballots were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 6 Activities Approved by the GCS between meetings of the TC Chapter

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

Table 7 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 8 Authorized Ballots

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
None			

Table 9 SNARF(s) Granted a One-Year Extension

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
6504	SDT TF	New Standard: Specification for Counterfeit Prevention for the Electronics Manufacturing Supply Chain	11/10/2024

Table 10 SNARF(s) Cancelled

<i>#</i>	<i>TF</i>	<i>Title</i>
None		

Table 11 Standard(s) to receive Inactive Status

<i>Standard Designation</i>	<i>Title</i>
None	

Table 12 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		

Table 13 Previous Meeting Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		



1 Welcome, Reminders, and Introductions

Dave Huntley (PDF Solutions) called the meeting to order at 4:05. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: Required Meeting Elements Nov 2022

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: Approve the minutes as written
By / 2nd: By: Eric Eisenbraun / AIM Photonics
Second: Takayuki Nishimura / SCREEN Semiconductor Solution Co., Ltd.
Discussion: None
Vote: 10-Y 0-N

Attachment: Trace-TC-Chapter-Minutes-July-2023

3 Liaison Reports

3.1 SEMI Staff Report

Michelle Sun (SEMI) gave the SEMI Staff Report. Of note:

2024 Calendar of Events

- SEMICON Korea: Jan 31-Feb 2, 2024
- SEMICON China: March 20-22, 2024
- SEMICON SEA: May 28-30, 2024
- SEMICON West: July 9-11, 2024

Upcoming NA Meetings

- NA Standards Spring Meetings
 - o March 25-28, 2024
 - o SEMI HQ, Milpitas
- SEMICON West
 - o July 8-11, 2024
 - o Moscone Center, San Francisco

Critical Dates for SEMI Standards Ballots – 2023 & 2024

2023	Ballot Submission Deadline	Voting Opens	Voting Closes
Cycle 1	January 3	January 17	February 16
Cycle 2	February 1	February 14	March 15
Cycle 3	March 6	March 20	April 19
Cycle 4	April 24	May 8	June 7



Cycle 5	May 7	May 21	June 20
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SEMI Standards Publications

- Total SEMI Standards in portfolio: 1,085
- Includes 335 Inactive Standards

New Standards

Cycle	Designation	Title	Committee	Region
August 2023	SEMI P49 (Preliminary)	Specification for Experimental Curvilinear Multigon Extension to SEMI P39	Micropatterning	NA
August 2023	SEMI PV101	Guide for Scrap Judgement of Photovoltaic Modules in Building	Photovoltaic	CH
August 2023	SEMI D84	Test Method for Warm-Up Properties of Display Picture Quality	FPD – Metrology	JA
September 2023	SEMI F121	Guide for Evaluating Metrology for Particle Precursors in Ultrapure Water	Liquid Chemicals	NA
September 2023	SEMI C105	Guide for Trace Iron Analysis in High Purity 2- Propanol (IPA)	Process Chemicals	NA
September 2023	SEMI M93	Test Method for Quantifying Basal Plane Dislocation Density in 4H-SiC by X-Ray Diffraction Topography/Imaging	Compound Semiconductor Materials	EU

SVM – Addressing Critical Issues

- User Data Quality
 - o Problem – User Data in SVM shows incorrect information
 - o Cause – The SVM Login process has a separate User Database than the existing Online Ballot System and requires ongoing synchronization. Also affects <https://connect.semi.org>
- Progress
 - o Completed internal testing
 - o Documentation and Training in development
- Open Community Preview of the New Online Ballot System during Cycle 9, 2023
- Committee Members to become familiar with new interface and provide feedback
- Open New Online Ballot System for Live Ballot voting for Cycle 1, 2024

Attachment: Trace Staff Report Nov 2023



4 Ballot Review

NOTE 1: TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

4.1 Document #7136, Reapproval of SEMI T3-1213 (Reapproved 0419), Specification for Wafer Box Labels

Attachment: AR - 7136

5 Subcommittee and Task Force Reports

5.1 Single Device Traceability (SDT) Task Force

Dave Huntley (PDF Solutions) reported for the SDT Task Force. Of note:

- SEMI SNARF #6504 (blockchain traceability) was put on hold pending input from GSA TIES. The 6504 concept was shared with GSA TIES and was included in a white paper generated by that activity (see attached). The 6504 concept was accepted by the GSA TIES members, and it was agreed that this should be standardized. SEMI represents the upstream steps (i.e., wafer design fab, package assembly and test) in the supply chain and therefore was the obvious choice of standards organization to develop this standard.
- To continue the development of this document, the SDT Task Force will resume its meetings every month. If anyone is interested in joining, please contact Michelle Sun at msun@semi.org.

Attachment: WP19 - Using the Virtual Identifier Thread for Reliability and Security 0_19 Draft Clean

6 Next Meeting and Adjournment

The next meeting is TBD. See <http://www.semi.org/standards-events> for the current list of events.

Adjournment: 4:59.

Respectfully submitted by:

Michelle Sun
 Coordinator
 SEMI North America
 Phone: 408.943.7982
 Email: msun@semi.org

Minutes tentatively approved by:

<Name> (<Company>), Co-chair	<Date approved>
<Name> (<Company>), Co-chair	<Date approved>

Table 14 Index of Available Attachments^{#1}

<i>Title</i>	<i>Title</i>
Required Meeting Elements Nov 2022	Trace Staff Report Nov 2023



Table 14 Index of Available Attachments#1

Trace-TC-Chapter-Minutes-July-2023	WP19 - Using the Virtual Identifier Thread for Reliability and Security 0_19 Draft Clean
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#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.